SLOVENSKI STANDARD
oSIST prEN IEC 63608-1:2026

01-junij-2026

Polprevodniški elementi - Preskusne metode zanesljivosti za vibracijske energetske zbiralnike - 1. del: Mehanska zanesljivost pri udarcih

Semiconductor devices - Reliability test methods for vibration energy harvesters - Part 1: Mechanical reliability under shock

Ta slovenski standard je istoveten z: **prEN IEC 63608-1:2026**

ICS:

31.080.99	Drugi polprevodniški elementi	Other semiconductor devices

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COMMITTEE DRAFT FOR VOTE (CDV)

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IEC TC 47 : SEMICONDUCTOR DEVICES	
SECRETARIAT: Korea, Republic of	SECRETARY: Mr Cheolung Cha
OF INTEREST TO THE FOLLOWING COMMITTEES:	HORIZONTAL FUNCTION(S):
ASPECTS CONCERNED:	
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TITLE:

Semiconductor devices - Reliability test methods for vibration energy harvesters - Part 1: Mechanical reliability under shock

PROPOSED STABILITY DATE: 2031

NOTE FROM TC/SC OFFICERS:

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DEVICES – RELIABILITY TEST METHODS FOR VIBRATION ENERGY HARVESTERS –
Part 1: Mechanical Reliability Under Shock

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